

Power MOSFET

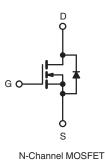
PRODUCT SUMMARY					
V _{DS} (V)	950				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 2.0				
Q _g (Max.) (nC)	190				
Q _{gs} (nC)	23				
Q _{gd} (nC)	110				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-Source Voltage		V_{DS}	950	V		
Gate-Source Voltage		V_{GS}	± 20	7 v		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 100 ^{\circ}\text{C}$		6.1			
Continuous Drain Current	ID	3.9	Α			
Pulsed Drain Current ^a		I _{DM}	24	1		
Linear Derating Factor			1.5	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	800	mJ			
Repetitive Avalanche Current ^a	I_{AR}	6.0	Α			
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ			
Maximum Power Dissipation	P_{D}	190	W			
Peak Diode Recovery dV/dtc	dV/dt	1.0	V/ns			
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)		300 ^d				
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in		
wounting rorque	0-32 OF MIS SCIEW		1.1	N⋅m		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=40~mH, $R_g=25~\Omega$, $I_{AS}=6.1~A$ (see fig. 12). c. $I_{SD}\leq 6.1~A$, $dI/dt\leq 120~A/\mu s$, $V_{DD}\leq 600$, $T_J\leq 150~^{\circ}C$. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		1				·	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		950	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I _D = 1 mA	-	1.2	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	_{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	_S = ± 20 V	-	-	± 100	nA
Zero Osto Vellana Buria Osmal	_	V _{DS} = 9	$V_{DS} = 950 \text{ V}, V_{GS} = 0 \text{ V}$		-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 760 V, V	/ _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 3.6 A ^b	-	2.0	-	Ω
Forward Transconductance	9fs	V _{DS} = 10	00 V, I _D = 3.6 A ^b	5.4	-	-	S
Dynamic						•	
Input Capacitance	C _{iss}	V	_{GS} = 0 V,	-	2800	-	
Output Capacitance	C _{oss}	V	os = 25 V,	-	250	-	рF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 I	MHz, see fig. 5	-	84	-	
Total Gate Charge	Qg			-	-	190	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 6.1 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	23	
Gate-Drain Charge	Q_{gd}		see lig. 6 and 13-		-	110	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 500 \text{ V, } I_D = 6.1 \text{ A,}$ $R_g = 6.2 \ \Omega, \ R_D = 81 \ \Omega, \ \text{see fig. } 10^b$		-	19	-	ns
Rise Time	t _r			-	35	-	
Turn-Off Delay Time	t _{d(off)}			-	130	-	
Fall Time	t _f			-	36	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") fro	Between lead, 6 mm (0.25") from		5.0	-	-11
Internal Source Inductance	L _S	package and center of die contact		-	13	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbo	MOSFET symbol showing the		-	6.1	A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	24	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 6.1 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 6.1 A, dI/dt = 100 A/μs ^b		-	630	950	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.5	5.3	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-	e (turn-on is dominated by L _S and L _D)			L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

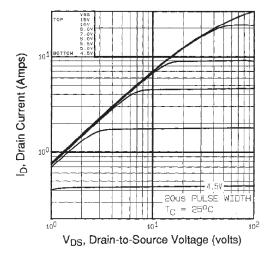


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

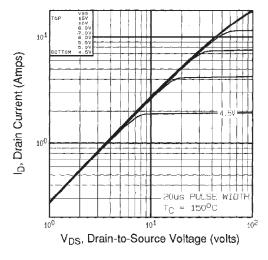
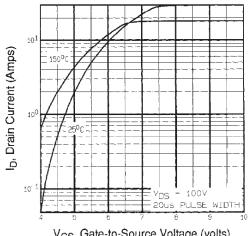


Fig. 2 - Typical Output Characteristics, T_C = 150 °C



V_{GS}, Gate-to-Source Voltage (volts)

Fig. 3 - Typical Transfer Characteristics

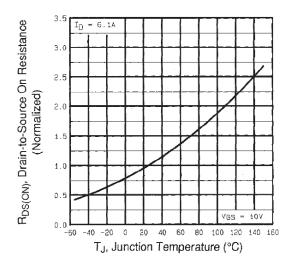


Fig. 4 - Normalized On-Resistance vs. Temperature



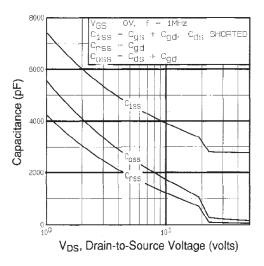


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

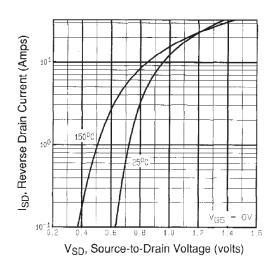


Fig. 7 - Typical Source-Drain Diode Forward Voltage

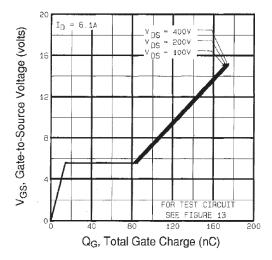


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

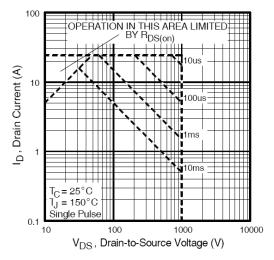


Fig. 8 - Maximum Safe Operating Area



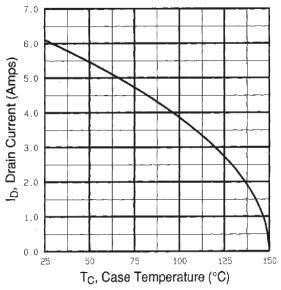


Fig. 9 - Maximum Drain Current vs. Case Temperature

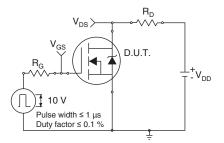


Fig. 10a - Switching Time Test Circuit

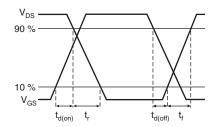


Fig. 10b - Switching Time Waveforms

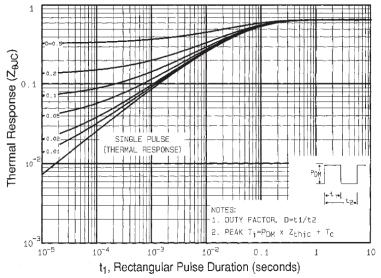
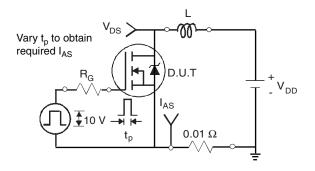


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case





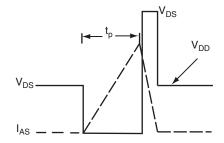


Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

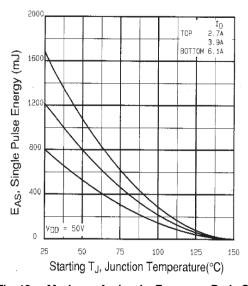


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

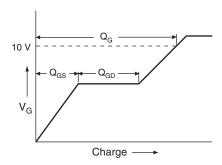


Fig. 13a - Basic Gate Charge Waveform

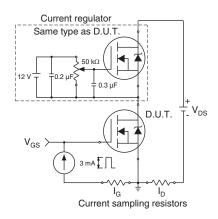
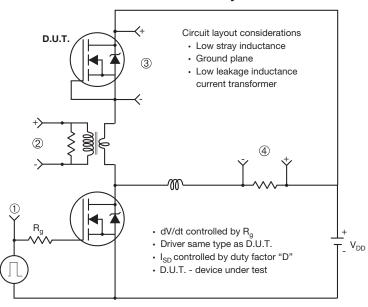


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



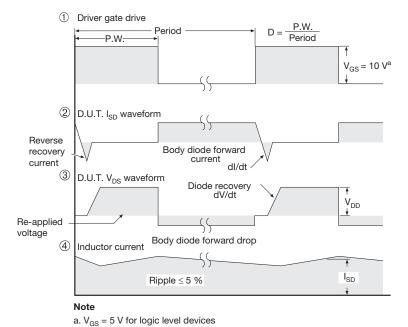
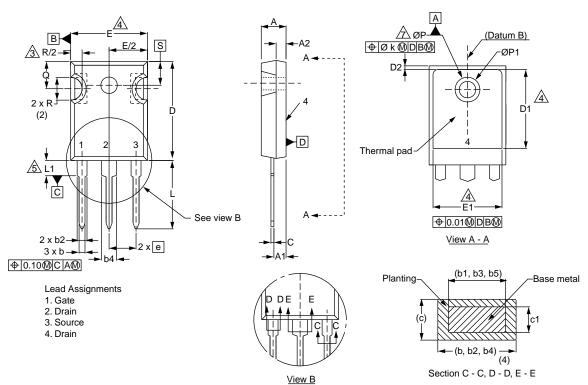


Fig. 14 - For N-Channel



TO-247AC (High Voltage)



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D2	0.51	1.30	0.020	0.051
E	15.29	15.87	0.602	0.625
E1	13.72	ı	0.540	ı
е	5.46 BSC		0.215 BSC	
Øk	0.254		0.010	
L	14.20	16.25	0.559	0.640
L1	3.71	4.29	0.146	0.169
Ν	7.62 BSC		0.300 BSC	
ØΡ	3.51	3.66	0.138	0.144
Ø P1	-	7.39	-	0.291
Q	5.31	5.69	0.209	0.224
R	4.52	5.49	0.178	0.216
S	5.51 BSC		0.217	BSC



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